

AMENDMENTS TO THE CLAIMS:

Please amend the claims as follows:

1. (Currently amended) An accelerated test method for evaluating, under accelerated conditions (a temperature T_2 and a voltage V_2), an endurance characteristic of a ferroelectric memory device comprising a capacitor element having a ferroelectric film under actual operating conditions (a temperature T_1 and a voltage V_1), the method comprising the step of:

deriving an acceleration factor (K) required to evaluate the endurance characteristic by using [[an]] a following expression (1):

$$\log K = A(1/V_1 - 1/V_2) + B(1/V_1 T_1 - 1/V_2 T_2) \quad (1)$$

(where each of A and B is a constant),

the method further comprising the sub-steps:

determining the number (L_c) of occurrences of polarization inversion when a remanence of the ferroelectric film reaches a specified decrease rate at each of a plurality of polarization inversion voltages (V) at a plurality of temperatures;

determining a constant (α) at a specified temperature (T) by using a following expression (2):

$$\log L_c = C + \alpha/V \text{ (where each of C and } \alpha \text{ is a constant)} \quad (2); \text{ and}$$

determining the constants A and B by using a following expression (3):

$$\alpha = A + B/T \quad (3).$$

2-3. (Cancelled)